

L Number	Hits	Search text	DB	Time stamp
1	155570	(resistance) with (temperature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:42
2	14471	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:43
3	976	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) and ((resistance) with (temperature))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:45
4	53	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) and ((resistance) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:51
5	13993	"shape memory alloy" or "shape memory alloys"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:59
6	0	("shape memory alloy" or "shape memory alloys") with "multi-chip package"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:59
7	0	("shape memory alloy" or "shape memory alloys") same "multi-chip package"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:59
8	3	("shape memory alloy" or "shape memory alloys") and "multi-chip package"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:59
9	45	("shape memory alloy" or "shape memory alloys") same ("integrated circuit" or "integrated circuits")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:00
10	283	((resistance) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same (epoxy or resin or resins)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:53

11	312	((resistance) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same (epoxy or resin or resins or solder or solders)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:06
12	0	((resistance) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same (epoxy or resin or resins or solder or solders) same ((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:08
13	110	solder-reflow	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:08
14	5478	solder-reflow or "solder reflow" or solder/reflow or solder-re-flow or "solder re-flow" or solder/re-flow	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:11
15	198	(solder-reflow or "solder reflow" or solder/reflow or solder-re-flow or "solder re-flow" or solder/re-flow) with (test or testing or tested or tester or testers or tests)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:52
24	173	cole.in. and epoxy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:18
25	97	sandia.asn. and epoxy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:20
26	11	sandia.asn. and cole.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 09:20
27	4	("5422498" "5430305" "5708371" "5844416").PN.	USPAT	2003/09/15 09:24
28	22	5422498.URPN.	USPAT	2003/09/15 09:25
29	3	("4874251" "5042952" "5049811").PN.	USPAT	2003/09/15 09:25
30	1	"4698587".PN.	USPAT	2003/09/15 09:33
31	3	((solder-reflow or "solder reflow" or solder/reflow or solder-re-flow or "solder re-flow" or solder/re-flow) with (test or testing or tested or tester or testers or tests)).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:01

32	2	(solder-reflow or "solder reflow" or solder/reflow or solder-re-flow or "solder re-flow" or solder/re-flow) with (test or testing or tested or tester or testers or tests) and ((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:01
33	283	((solder-reflow or "solder reflow" or solder/reflow or solder-re-flow or "solder re-flow" or solder/re-flow)).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:01
34	1	(solder-reflow or "solder reflow" or solder/reflow or solder-re-flow or "solder re-flow" or solder/re-flow).ti. and ((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:50
35	0	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) with "change in resistance"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:51
36	173	"wiring defects"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:52
37	0	"wiring defects" and ((resistance or resistance or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:53
38	5522	((resistance or resistance or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:54
39	0	((resistance or resistance or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same ((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 10:54

40	40	((resistance or resistance or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same (((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) or ((short or shorted or open or opened) with (circuit or circuits or circuited or circuited)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:00
41	151	"reflow test" or "reflow tests" or "reflow testing" or "reflow tested" or "re-flow test" or "re-flow tests" or "re-flow testing" or "re-flow tested"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:08
42	480	"temperature cycle test"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:09
43	1	"temperature cycle test".ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:10
44	568	"temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:23
45	2	("4,695,404").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:11
46	20	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") and ((resistance or resistance or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:13

48	3	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") and (((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) or (((short or shorted) and (open or opened)) with (circuit or circuits or circuited or circuited)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:22
47	125	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") and (((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) or ((short or shorted) and (open or opened)) with (circuit or circuits or circuited or circuited)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:23
50	5500	"temperature cycling"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:47
49	1	"temperature cyclying"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:46
51	2	"temperature cycling" and ((resistance or resistence or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables)) same (((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (open-circuit or open-circuits or open-circuited or open-circuiting or "open circuit" or "open circuits" or "open circuited" or "open circuiting")) or ((short or shorted or open or opened) with (circuit or circuits or circuited or circuited)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 11:49
52	67	"temperature cycling" and ((resistance or resistence or resistivity or resistivities) with (temperature or degree or degrees) with (plot or plots or plotted or plotting or graph or graphs or graphed or graphing or table or tables))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:11

54	0	espec.asn. and "solder connections"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:11
55	0	espec.asn. and solder	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:22
56	2	("5920504").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:23
57	2	("5902504").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:23
58	2	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") with (continuous or continuously)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 12:26
59	0	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") and espec.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 13:37
53	815	espec.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 13:18
60	51487	ishii.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 13:18
61	403	ishii.in. and solder	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 13:18
62	7	("temperature cycle test" or "temperature-cycle test" or "temperature cycle tested" or "temperature-cycle tested" or "temperature cycle testing" or "temperature-cycle testing" or "temperature cycle tests" or "temperature-cycle tests") with (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:42
64	162	702/99.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
65	545	702/117.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50

66	144	702/118.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
67	140	702/119.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
68	127	702/120.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
69	536	702/130.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
70	61	702/133.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
71	67	702/134.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
72	39	702/135.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
73	250	702/136.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
74	152	324/703.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
75	529	324/760.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:50
76	235	(702/99.ccls. 702/117.ccls. 702/118.ccls. 702/119.ccls. 702/120.ccls. 702/130.ccls. 702/133.ccls. 702/134.ccls. 702/135.ccls. 702/136.ccls. 324/703.ccls. 324/760.ccls.) and @pd>=20030201	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 14:56
77	2	("5,419,780").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:11
78	713	(Peltier-junction or peltier) and (heatsink or heat-sink or "heat sink" or heatsinks or heat-sinks or "heat sinks") and (fan or fans)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:12
79	274	(Peltier-junction or peltier) same (heatsink or heat-sink or "heat sink" or heatsinks or heat-sinks or "heat sinks") same (fan or fans)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:12

80	6	(Peltier-junction or peltier) same (heatsink or heat-sink or "heat sink" or heatsinks or heat-sinks or "heat sinks") same (fan or fans) same (program or programs or programmed or programming)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:14
81	274	(Peltier-junction or peltier) same (heatsink or heat-sink or "heat sink" or heatsinks or heat-sinks or "heat sinks") same (fan or fans)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:15
82	58	((Peltier-junction or peltier) same (heatsink or heat-sink or "heat sink" or heatsinks or heat-sinks or "heat sinks") same (fan or fans)) and (pcb or circuit-board or circuit-boards or "circuit board" or "circuit boards") ("5,457,342").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:36
83	2	("5,457,342").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:29
84	2	("4,685,081").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:29
85	27	((Peltier-junction or peltier) same (heatsink or heat-sink or "heat sink" or heatsinks or heat-sinks or "heat sinks") same (fan or fans)) and (pcb or circuit-board or circuit-boards or "circuit board" or "circuit boards")) and (program or programs or programmed or programming or programmable) ("5107325").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:57
86	1	("5107325").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 15:57
-	2	("4576322").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/15 08:41
-	12557	peltier	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:26
-	5	peltier-junction	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:26
-	113	("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's").ti. and peltier	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:28
-	8	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)).ti. and peltier	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:30
-	375	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:31

-	83	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and (fan or fans)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:32
-	0	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and (fan or fans) and ("power bus" or "power busses"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:32
-	0	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and ("power bus" or "power busses") and "ground resistance"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:33
-	3	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and (test or tests or testing or tested or tester or tester)) and peltier and ("power bus" or "power busses"))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:33
-	0	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") same (test or tests or testing or tested or tester or tester)) and (power with bus with ground with resistance with temperature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:34
-	0	((("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") same (test or tests or testing or tested or tester or tester)) and (bus with ground with resistance with temperature)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:35
-	0	"power bus to ground"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:35
-	141	"power bus" with resistance	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:37
-	4	("power bus" with resistance) same temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:39
-	293	(bus with resistance) same temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 15:39
-	152	(bus with resistance) with temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:42
-	29	("3979671" "3986337" "4089184" "4134447" "4172993" "4253515" "4324285" "4402185" "4426619" "4579527" "4604572" "4607220" "4612772" "4636726" "4727720" "4734872" "4759190" "4780086" "4839587" "5006796" "5028988" "5184068" "5424209" "5510724" "5767489" "5844208" "5903163" "5966940" "6095293").PN.	USPAT	2003/02/12 15:50

-	53	"power bus" with temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:44
-	2	"power bus" with temperatures	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:43
-	0	"power buses" with temperatures	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:43
-	13	"power buses" with temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:43
-	0	"power buses" with degrees	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:44
-	2	"power buses" with degree	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:44
-	13	"power bus" with degree	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:44
-	2	"power bus" with degrees	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/12 16:44
-	80	"power bus" with temperature) ("power bus" with temperatures) ("power buses" with temperatures) ("power buses" with temperature) ("power buses" with degrees) ("power buses" with degree) ("power bus" with degree) ("power bus" with degrees	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 07:50
-	5345	bus with temperature) (bus with temperatures) (buses with temperatures) (buses with degrees) (buses with degree) (bus with degree) (bus with degrees	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 07:55
-	5345	bus with temperature) (bus with temperatures) (buses with temperatures) (buses with temperature) (buses with degrees) (buses with degree) (bus with degree) (bus with degrees	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 07:58
-	1041	((bus with temperature) (bus with temperatures) (buses with temperatures) (buses with temperature) (buses with degrees) (buses with degree) (bus with degree) (bus with degrees)).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 09:12
-	1827	(plot or plots or plotting or plotted or graph or graphs or graphing or graphed) with (temperature or temperatures) with (resistance or resistances)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 10:59
-	2156	(plot or plots or plotting or plotted or graph or graphs or graphing or graphed) with (temperature or temperatures) with (voltage or voltages)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 10:11

-	0	(plot or plots or plotting or plotted or graph or graphs or graphing or graphed) with (temperature or temperatures) with (voltage or voltages) with (bus or busses)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 10:12
-	729	((plot or plots or plotting or plotted or graph or graphs or graphing or graphed) with (temperature or temperatures) with (voltage or voltages)) and (test or tests or tested or testing or tester or testers)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 10:15
-	804	((plot or plots or plotting or plotted or graph or graphs or graphing or graphed) with (temperature or temperatures) with (resistance or resistances)) and (test or tests or tested or testing or tester or testers)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 12:03
-	19	4734641.URPN.	USPAT	2003/02/13 11:52
-	58	"thermal evaluation"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 12:05
-	10	"3982918"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 12:05
-	2	("3982918").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 12:05
-	2	("3982218").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:25
-	7	bus-to-ground	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:29
-	3253	unisys.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:26
-	5150	bus near3 ground	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:32
-	13	(bus near3 ground) and unisys.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:30
-	1	(bus near3 ground) and unisys.asn. and temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:30
-	12115	bus near3 voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:32

-	30	(bus near3 voltage) and unisys.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:32
-	1	(bus near3 voltage) and unisys.asn. and temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:32
-	1	(bus near3 resistance) and unisys.asn. and temperature	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:33
-	3	(bus near3 resistance) and unisys.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:37
-	119	702/118.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:37
-	117	702/119.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:37
-	101	702/120.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:37
-	3372	((test or tests or testing or tester or tested or testers) and ("circuit board" or "circuit boards" or pcb)).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 13:41
-	114	((test or tests or testing or tester or tested or testers) and ("circuit board" or "circuit boards" or pcb)).ti. and (heat or heats or heating or heated or heater or heater or temperature or temperatures).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:18
-	32	4792683.URPN.	USPAT	2003/02/13 13:55
-	150	324/703.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:19
-	476	324/760.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:20
-	150	702/99.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:20
-	504	702/130.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:21

-	60	702/133.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:21
-	61	702/134.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:21
-	38	702/135.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:21
-	237	702/136.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 14:21
-	493	702/117.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 15:55
-	16	702/117.ccls. and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 15:59
-	1045	(702/118.ccls. 702/119.ccls. 702/120.ccls. 324/703.ccls. 324/760.ccls. 702/99.ccls. 702/130.ccls. 702/133.ccls. 702/134.ccls. 702/135.ccls. 702/136.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:20
-	5	(702/118.ccls. 702/119.ccls. 702/120.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:01
-	116	(702/99.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02
-	399	(702/130.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02
-	47	(702/133.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02
-	51	(702/134.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02
-	35	(702/135.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02

-	102	(702/136.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02
-	78	(324/703.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:02
-	276	(324/760.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 16:10
-	191	(702/118.ccls. 702/119.ccls. 702/120.ccls. 324/703.ccls. 324/760.ccls. 702/99.ccls. 702/130.ccls. 702/133.ccls. 702/134.ccls. 702/135.ccls. 702/136.ccls.) and (heat or heats or heater or heated or heaters or heating or temperature or temperatures or degree or degrees).ab. and (resistance or resistances or resistor or resistors or resistivity or resistivities or conduct or conducts or conducts or conducting or conducted or conductivity or conductivities or resist or resists or resisting or resisted).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 17:26
-	83407	(resistance or resistances or resistor or resistors or resistivity or resistivities) near3 surface	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 17:27
-	164	((resistance or resistances or resistor or resistors or resistivity or resistivities) near3 surface) same bus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 17:28
-	51	(US-4576322-\$ or US-6215323-\$ or US-4251336-\$ or US-4956605-\$ or US-4706010-\$ or US-6229329-\$ or US-6300862-\$ or US-6469497-\$ or US-6438821-\$ or US-6437634-\$ or US-6362721-\$ or US-6288597-\$ or US-6278313-\$ or US-6104274-\$ or US-5852445-\$ or US-5801612-\$ or US-6215324-\$ or US-4734641-\$ or US-5302022-\$ or US-5130644-\$ or US-3982218-\$ or US-6238086-\$ or US-5182629-\$ or US-5696450-\$ or US-5543727-\$ or US-5172063-\$).did. or (US-4792683-\$ or US-6422741-\$ or US-6360935-\$ or US-5733041-\$ or US-5006788-\$ or US-5392219-\$ or US-6140825-\$ or US-5760595-\$ or US-5698987-\$ or US-5260668-\$ or US-RE32625-\$ or US-4739258-\$ or US-6329831-\$ or US-5451885-\$ or US-4483629-\$ or US-5657394-\$).did. or (EP-408863-\$ or EP-283778-\$).did. or (JP-04144248-\$ or JP-04104072-\$ or JP-01286322-\$ or JP-06347500-\$ or JP-03255966-\$ or JP-01046638-\$).did. or (NN81092167).tban.	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2003/02/13 17:31

-	5	((US-4576322-\$ or US-6215323-\$ or US-4251336-\$ or US-4956605-\$ or US-4706010-\$ or US-6229329-\$ or US-6300862-\$ or US-6469497-\$ or US-6438821-\$ or US-6437634-\$ or US-6362721-\$ or US-6288597-\$ or US-6278313-\$ or US-6104274-\$ or US-5852445-\$ or US-5801612-\$ or US-6215324-\$ or US-4734641-\$ or US-5302022-\$ or US-5130644-\$ or US-3982218-\$ or US-6238086-\$ or US-5182629-\$ or US-5696450-\$ or US-5543727-\$ or US-5172063-\$).did. or (US-4792683-\$ or US-6422741-\$ or US-6360935-\$ or US-5733041-\$ or US-5006788-\$ or US-5392219-\$ or US-6140825-\$ or US-5760595-\$ or US-5698987-\$ or US-5260668-\$ or US-RE32625-\$ or US-4739258-\$ or US-6329831-\$ or US-5451885-\$ or US-4483629-\$ or US-5657394-\$).did. or (EP-408863-\$ or EP-283778-\$).did. or (JP-04144248-\$ or JP-04104072-\$ or JP-01286322-\$ or JP-06347500-\$ or JP-03255966-\$ or JP-01046638-\$).did. or (NN81092167).tban.) and "power bus"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/13 17:31
-	118	"bus resistance"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 08:39
-	2	("bus resistance" or "bus resistances") with (temperature or temperatures)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 08:40
-	94	("bus voltage" or "bus voltages") with (temperature or temperatures)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 08:41
-	32	4792683.URPN.	USPAT	2003/02/21 08:56
-	4	("3808439" "4240750" "4481418" "4647220").PN.	USPAT	2003/02/21 08:56
-	6	4380725.URPN.	USPAT	2003/02/21 09:02
-	0	6426484.URPN.	USPAT	2003/02/21 09:09
-	21	("4256945" "4448306" "4623401" "4695713" "4701587" "4717814" "4745264" "4769525" "4792683" "5010233" "5117279" "5175409" "5194695" "5239806" "5418189" "5498899" "5500555" "5521426" "5598031" "5938956" "6111220").PN.	USPAT	2003/02/21 09:09
-	0	6422741.URPN.	USPAT	2003/02/21 09:10
-	13	("4679946" "4792683" "4866276" "5111048" "5228776" "5562345" "5574379" "5698978" "5706094" "5748003" "5886534" "5952561" "6173604").PN.	USPAT	2003/02/21 09:10
-	0	6360935.URPN.	USPAT	2003/02/21 09:11

-	28	("4227415" "4409333" "4467638" "4657169" "4657196" "4696104" "4792683" "4941256" "5089700" "5118945" "5148375" "5206705" "5208528" "5246291" "5250809" "5262022" "5357346" "5401380" "5407275" "5425859" "5446549" "5574801" "5676302" "5836504" "5912984" "5963662" "5971249" "5988487").PN.	USPAT	2003/02/21 09:11
-	6	("voltage drop" with temperature) same epoxy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 09:18
-	347	(voltage with temperature) same epoxy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 09:19
-	109	(voltage with temperature) with epoxy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 09:41
-	21	5246291.URPN.	USPAT	2003/02/21 09:20
-	5	("3803413" "4792683" "4999499" "5052816" "5064291").PN.	USPAT	2003/02/21 09:20
-	19	5963662.URPN.	USPAT	2003/02/21 09:32
-	2	("3795918" "5115475").PN.	USPAT	2003/02/21 09:32
-	2	5836504.URPN.	USPAT	2003/02/21 09:36
-	5	("5012502" "5291535" "5463667" "5561696" "5592562").PN.	USPAT	2003/02/21 09:36
-	83832	short-circuit or short-circuits or short-circuited or short-circuiting	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:21
-	1094	(short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 09:42
-	232	((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:23
-	36	((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:23
-	196	((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 09:58

-	169768	short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:22
-	112	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:33
-	567	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:32
-	576	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:29
-	76	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)) not (((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:24
-	575	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) not (((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers)) not (((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures)) and (test or tests or testing or tested or tester or testers))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:28

-	2	("4,851,946").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:28
-	335	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures) not ((short-circuit or short-circuits or short-circuited or short-circuiting) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:29
-	301	((bridging or bridge or bridges or bridged) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures) and (test or tests or testing or tested or tester or testers)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:40
-	15	((bridging or bridge or bridges or bridged) with (solder or epoxy)) same (heat or heats or heating or heated or temperature or temperatures) and (test or tests or testing or tested or tester or testers or monitor or monitors or monitoring or monitored or determine or determining or determines or determined or determination or determinations).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 10:41
-	0	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same ("surface temperature")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:33
-	0	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (solder or epoxy)) same ("surface resistance")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:34
-	3254	UNISYS.asn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:36
-	36	UNISYS.asn. and (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:42
-	2	("4938410").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:07
-	4	("1949716" "3752642" "4757800" "4771929").PN.	USPAT	2003/02/21 11:43
-	253	"high acceleration stress test" or hast	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:50

-	2	("high acceleration stress test" or "highly accelerated stress test" or "high acceleration stress tests" or "highly accelerated stress tests" or hast) with (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:54
-	3	("high acceleration stress test" or "highly accelerated stress test" or "high acceleration stress tests" or "highly accelerated stress tests" or "high acceleration saturation test" or "high acceleration saturation tests" or "highly accelerated saturation test" or "highly accelerated saturation tests" or hast) same (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:56
-	118	"burn-in" same (short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 11:57
-	513	((test or testing or tests or tester or testers) and (solder or soldering or solders)).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:17
-	4	((test or testing or tests or tester or testers) and (solder or soldering or solders)).ti. and "heat sink"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:11
-	105	((test or testing or tests or tester or testers) and (solder or soldering or solders)).ti. and (temperature or temperatures or heat or heats or heating or heated).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:15
-	4	("6323663").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:15
-	100	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") and (solder or soldering or solders)).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 13:19
-	945	("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and peltier	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 17:09
-	187	("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's") and peltier and (fan or fans)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 17:14
-	29	("integrated circuit" or "integrated circuits" or "ic" or "ics" or "ic's" or "circuit board" or "circuit boards" or "pcb") and peltier and (fan or fans) and ((temperature or temperatures) with (ramp or ramping or ramps or ramped))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/21 17:15

-	4	5760595.URPN.	USPAT	2003/02/23 13:31
-	4	5760595.URPN.	USPAT	2003/02/23 13:32
-	0	"shorts test".ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 13:34
-	75	"shorts test"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 13:39
-	27	"shorts test" and (temperature or temperatures or heat or heats or heating or heated)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 13:55
-	2	("4938410").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 13:56
-	2	("4938410").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 13:56
-	8	((("4938410") or ("5172063") or ("5696450") or ("5543727"))).PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 13:57
-	0	(short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with bus with ground with (resistance or resistances) with (plot or plots or plotting or plotted or plotting or graph or graphs or graphing or graphed or graphs)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:30
-	4	(short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with bus with ground with (resistance or resistances)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:29
-	0	(short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") same (bus with ground with (resistance or resistances) with (plot or plots or plotting or plotted or plotting or graph or graphs or graphing or graphed or graphs))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:30
-	10	(short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") same (bus with ground with (resistance or resistances))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:32
-	14370	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:34

-	969	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:36
-	0	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)) same "power bus"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:36
-	12	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)) same bus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:37
-	19	((short-circuit or short-circuits or short-circuited or short-circuiting or "short circuit" or "short circuits" or "short circuited" or "short circuiting") with (detect or detects or detecting or detected or detection or detections)) with (resistance or resistances or resitivity)) same ("circuit board" or "circuit boards" or pcb)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:45
-	2	("5844330").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 16:06
-	2	("6140825").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 14:46
-	2	("5,419,780").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 15:03
-	2	("6140825").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 16:08
-	2	("4739258").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 16:38
-	2	("4739258").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 16:53
-	2	("5419780").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 17:10

-	2	("6226994").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 17:16
-	1	("re 32625").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/23 17:16
-	2	("5419780").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/24 08:23